

Notice of References Cited	Application/Control No. 10/762,571		Applicant(s)/Patent Under Reexamination ABDEL-HAFEZ ET AL.	
	Examiner R. Stephen Dildine		Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0120896 A1	08-2002	Wang et al.	714/731
*	B	US-6,557,129 B1	04-2003	Rajski et al.	714/729
*	C	US-6,901,546 B2	05-2005	Chu et al.	714/729
*	D	US-6,543,018	04-2003	Adusumilli et al.	714/729
*	E	US-2003/0154433 A1	08-2003	Wang et al.	714/726
*	F	US-2004/0230884 A1	11-2004	Rajski et al.	714/742
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2005031378 A1	04-2005	WIPO	Vranken et al.	G01R 31/3185
	O	JP 2002122639 A	04-2002	Japan	HAPKE, FRIEDRICH	G01R 31/28
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Huang, Y. et al.; Statistical Diagnosis for Intermittent Scan Chain Hold-Time Fault; ITC INTERNATIONAL TEST CONFERENCE Paper 12.2; 2003; pages 319-328
	V	Liu, C. et al.; A Partition-Based Approach for Identifying Failing Scan Cells in Scan-BIST with Applications to System-on-Chip Fault Diagnosis; Proceedings of the Design, Automation and Test in Europe Conference and Exhibition; 2003; 6 unnumbered pages
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.